

Measurement Capabilities

Georgia Institute
of Technology

Exhaustive Device and Circuit Characterization Capability

- Integrated S-Parameters + Noise Figure + Load-pull System to 40 GHz
- SP + NF + 2-tone Linearity (50Ω) + Phase Noise + High Power to 67 GHz
- 75-110 GHz Circuit Measurement Capability (50Ω gain + noise + linearity)
- Close-in Phase Noise + AM-PM Test System (to 18 GHz)
- 4K – 400K, dc to 40 GHz, RF Cryogenic Test System
- Two 10K – 400K, dc to 100 MHz, Cryogenic Test Systems
- 300C High-Power Test System + Pulsed I-V Test System
- 1/f Noise Test System + Reliability / Stress (dc + RF) Test System
- Five Semiconductor Parameter Analyzers + 12 GHz Tektronix Scope
- Radiation Experiments + Packaging + All Design/Simulation Tools

